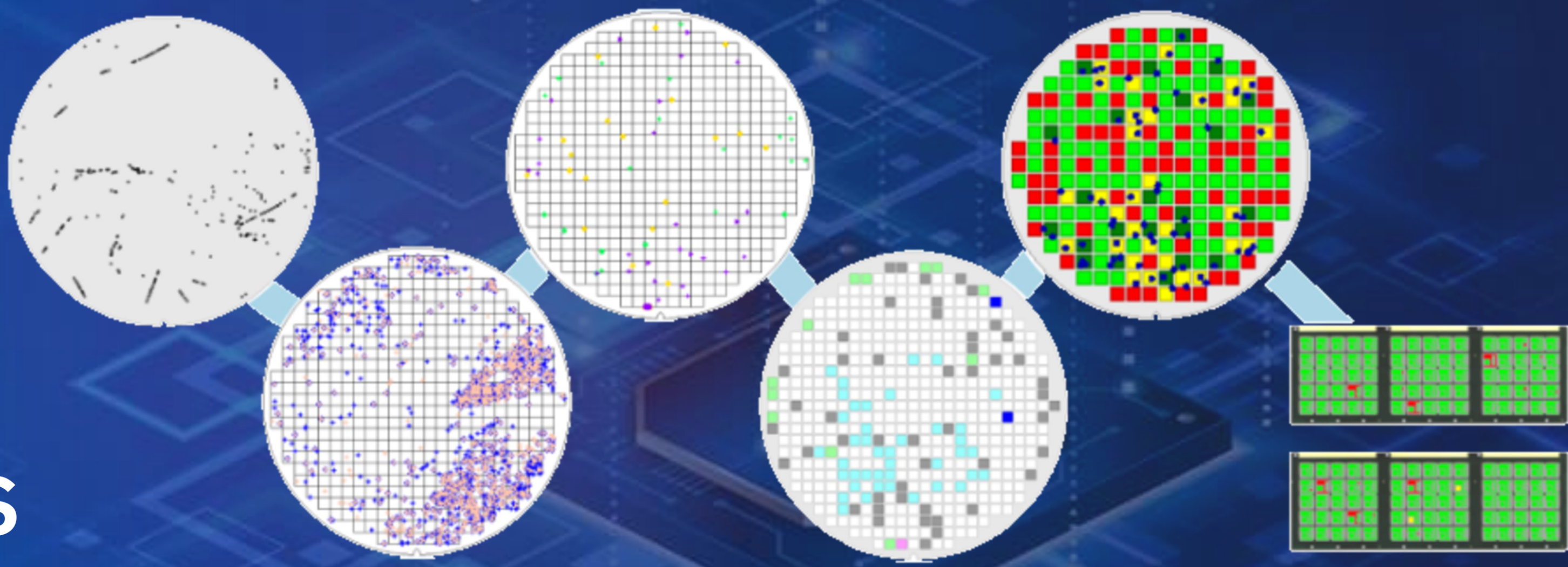


The **market-leading** yield management platform for faster ramp and engineering productivity at scale.



The Leading Yield Management Platform

PDF Solutions' Exensio® Manufacturing Analytics (EMA) is the semiconductor industry's **leading Yield Management System**, trusted by **400+ customers** across **20 countries** to accelerate yield ramp and engineering output across the end-to-end semiconductor value chain - from **design through test and system**.

Problem with **Status Quo**

Fragmented data across fab equipment, LIMS, and MES forces engineers to spend weeks on data preparation.

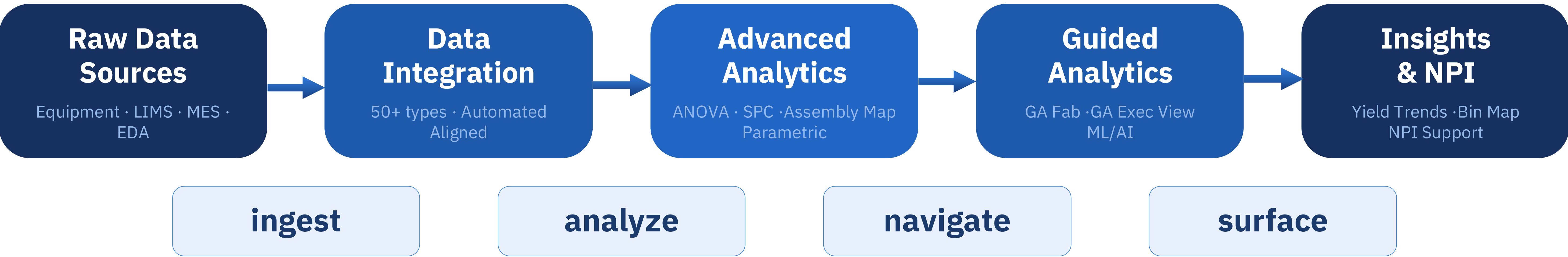
This leaves too little time for actual yield problem-solving.

Solution Highlights

- Unify fab data into a single **analytics-ready** layer
- Surface yield root causes with **AI-guided** analytics
- Multiply engineering output across **every fab node**

Components

- Advanced Analytics**
ANOVA, SPC, assembly maps, and parametric/bin mapping for deep fab process insights.
- Big Data Analytics**
Scalable retrieval and analytics for high-volume fab data across all process nodes.
- Guided Analytics**
AI-driven, hierarchical root-cause discovery with minimal user input in seconds.
- New Product Introduction**
Enables NPI with standard retrieval, bin map, and parametric map for new node ramps.



Use Cases

Accelerate Yield Ramp Across Sites

A semiconductor manufacturer used Exensio Manufacturing Analytics to **unify multi-site data** and apply **guided analytics**, enabling faster identification of yield issues during a BiCMOS node ramp.

30%
FASTER TIME TO YIELD TARGET



Challenge

Multi-site BiCMOS ramp with **siloeed data and manual analysis** bottlenecks slowing yield debug cycles.



Result

Yield target achieved **30% faster** than projected, with root causes surfaced in hours via EMA's guided analytics.



Challenge

Inconsistent KPI reporting and **redundant** analysis infrastructure across six OSAT test sites hindered yield compliance.

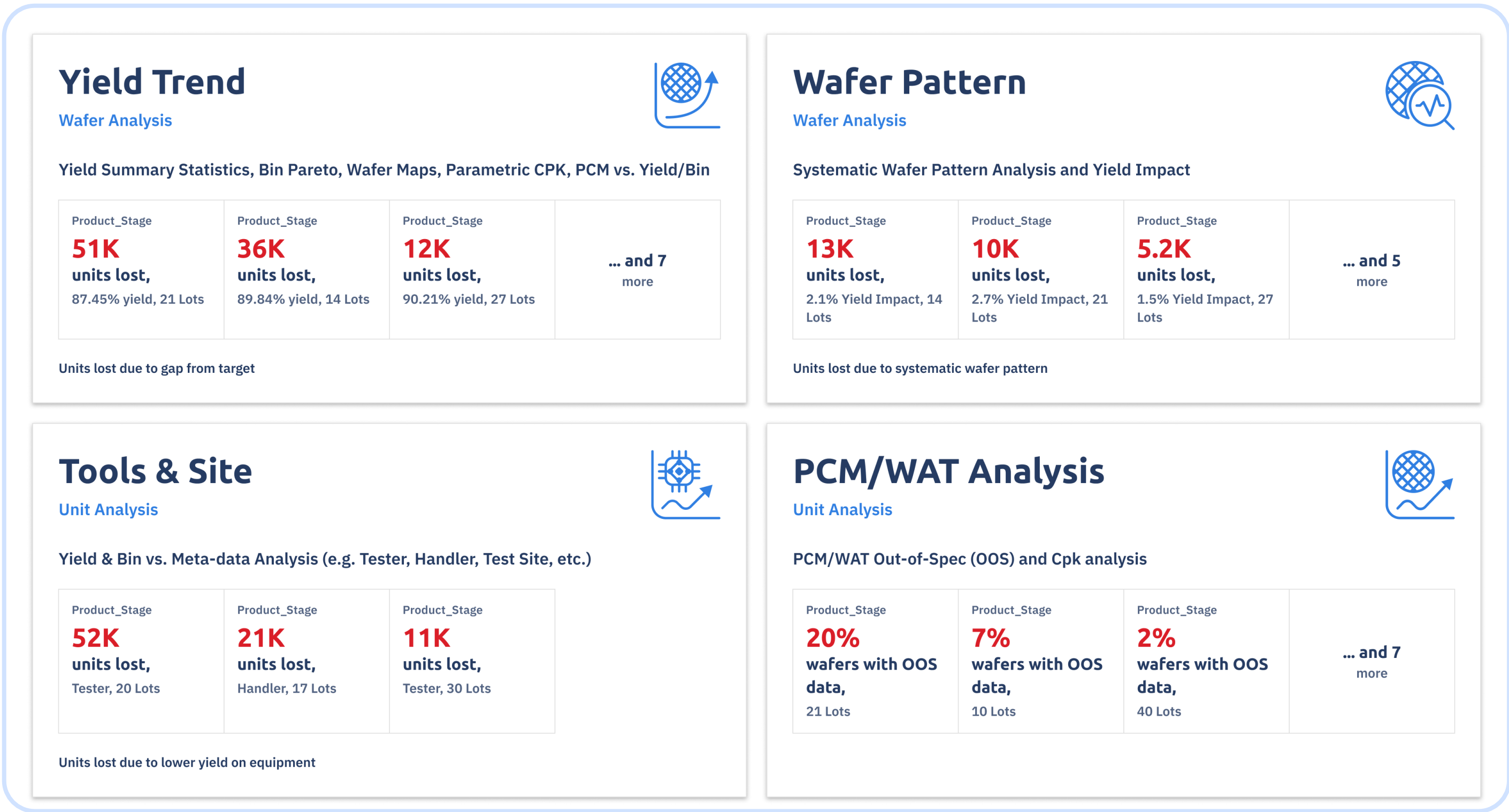


Result

Eliminated duplicate infrastructure. Teams aligned on **yield benchmarks** across all six OSAT sites with EMA.

Leading OSAT: Multi-Site Quality at Scale

A leading OSAT deployed EMA's **semantic data model** and **guided analytics** to unify die-level data and standardize KPI reporting across global test sites.



80%

reduction in data wrangling time

results based on typical Exensio customers

up to 5x

engineering efficiency improvement

up to 30%

faster time to yield target

Contact Us



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